

Figure 1: Growth structures for GaInP:Te SIMS profiling, grown on GaAs (001) substrates (not shown). Te pre-dose values indicated by dotted lines in monolayers (ML). (a) target $[Te] = 1.7 \times 10^{18} \text{ cm}^{-3}$ with GaAs spacer to absorb excess Te. (b) target $[Te] = 5.7 \times 10^{17} \text{ cm}^{-3}$ with unintentionally doped (UID) GaInP spacers to absorb excess Te.

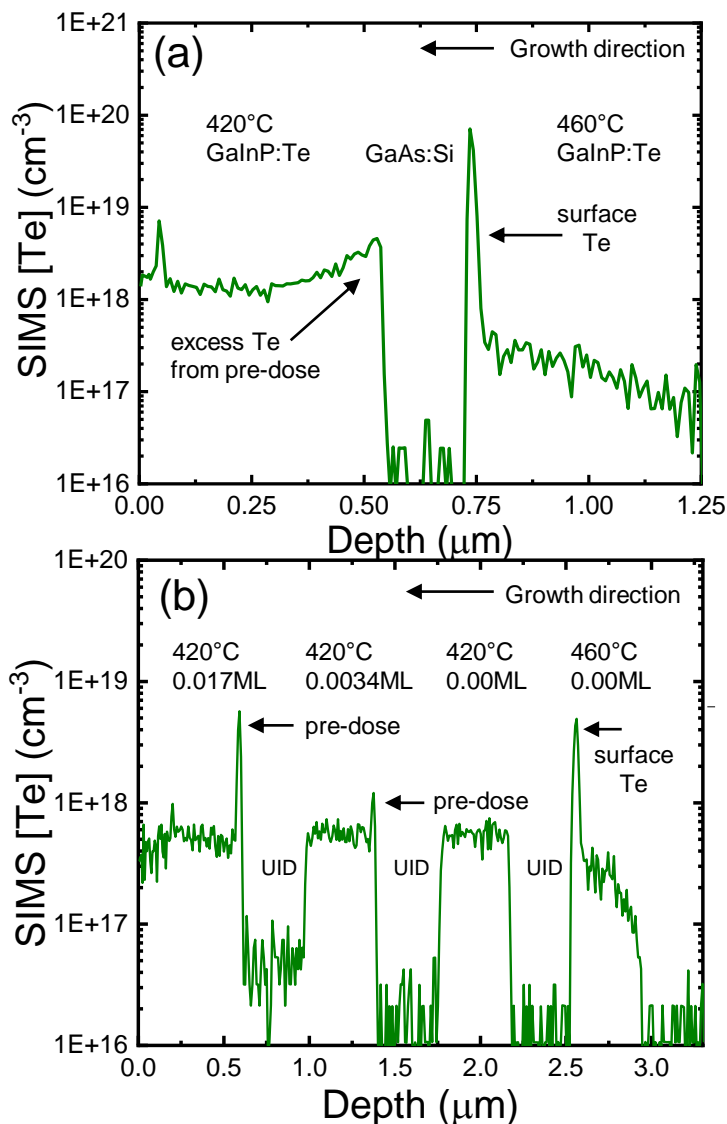


Figure 2: SIMS profiles corresponding to growth structures in Figure 1. (a) SIMS for target $[Te] = 1.7 \times 10^{18} \text{ cm}^{-3}$ shows greatly reduced but visible segregation at $T_{\text{sub}} = 420 \text{ }^\circ\text{C}$. (b) SIMS for $[Te] = 5.7 \times 10^{17} \text{ cm}^{-3}$ shows complete suppression of surface segregation at $T_{\text{sub}} = 420 \text{ }^\circ\text{C}$, as seen by abrupt Te pre-dose spikes.

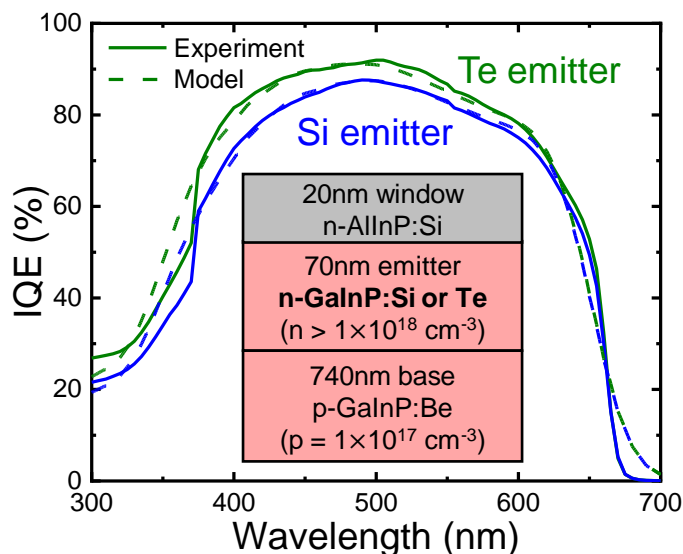


Figure 3: IQE of GaInP solar cells with GaInP:Si and GaInP:Te emitters, experimental (solid) and modeled (dotted). The model indicates a $\sim 4\times$ improved carrier lifetime for n-GaInP:Te. Inset simplified cell structure shows AllnP window and n/p GaInP absorber region.

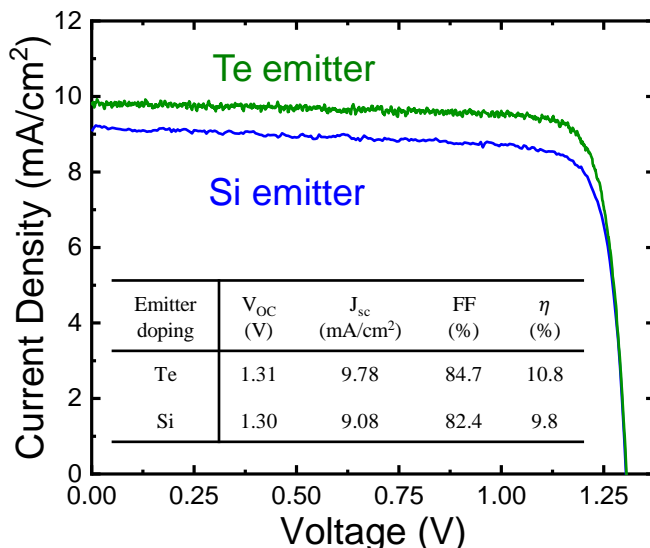


Figure 4: Lighted IV curves of GaInP cells with GaInP:Si and GaInP:Te emitters, and figures of merit of open-circuit voltage (V_{OC}), short-circuit current density (J_{sc}), fill factor (FF), and efficiency (η).

References in abstract

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